Search Notes



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Applicant(s)/Patent Under Reexamination

LEE, BAEK-WOON

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Art Unit

Sherman, Stephen G

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SEARCHED

Class	Subclass	Date	Examiner
345	88,600,603-605,613,87-102	11/29/2006	SS
349	56,82,84,109,143	11/29/2006	SS
349	139	4/16/2007	SS

SEARCH NOTES

Search Notes	Date	Examiner
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Search Updated	11/29/2006	SS
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INTERFERENCE SEARCH

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Class	Subclass	Date	Examiner

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